

## PCN# 20230406001.2 Qualification of RFAB as an additional Fab site option for select HPA07 devices Change Notification / Sample Request

Date:April 06, 2023To:TOKYO ELECTRON DEVICE (DSTR) PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

Texas Instruments requires acknowledgement of receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If samples or additional data are required, requests must be received within **30 days** of this notification.

The changes discussed within this PCN will not take effect any earlier than the proposed first ship date on Page 3 of this notification, unless customer agreement has been reached on an earlier implementation of the change.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice or to provide acknowledgement of this PCN, you may contact your local Field Sales Representative or the PCN Team (<u>PCN ww admin team@list.ti.com</u>). For sample requests or sample related questions, contact your local Field Sales Representative.

PCN Team SC Business Services

# **Products Affected:**

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

DEVICE	CUSTOMER PART NUMBER
DAC5311IDCKT	null
DAC6311IDCKT	null
DAC5311IDCKR	null
DAC7311IDCKR	null
DAC7311IDCKT	null
DAC8311IDCKT	null
DAC8411IDCKR	null
DAC8411IDCKT	null
DAC6311IDCKR	null

Technical details of this Product Change follow on the next page(s).

PCN Number:	<b>:</b> 20230406001.2 <b>PCN Date:</b> April 06, 2023						
Title:     Qualification of RFAB as an additional Fab site option for select HPA07 devices							
Customer Conta	ct: [	PCN Manager		Dept:	Qu	Quality Services	
Proposed 1 <sup>st</sup> Shi	p Date:	Oct 6, 2023	-	e Reque		y 6, 2023 <b>*</b>	
-	-			ed until		, 0, 2020	
*Sample reques Change Type:	ts received a	<u>πer May 6, 2</u>	023 WIII not be	suppor	iea.		
Assembly Site	e [	Assembly	Process		Assembly	Materials	
Design		/	Specification			al Specification	
Test Site	[		, hipping/Labeling		Test Proc		
Wafer Bump			mp Material		Wafer Bu	mp Process	
☑ Wafer Fab Sit	te	_	o Materials		Wafer Fab Process		
			ber change				
Description of C	hangai	PC	N Details				
<b>Description of C</b> Texas Instruments		announce th	e addition of REA	Bacana	ditional	Wafor Fab sito	
option for the proc							
Cu	rrent Fab Sit	е		New	Fab Site		
Current Fab Site	Process	Wafer Diameter	New Fab Site	Pro	ocess	Wafer Diameter	
DP1DM5	HPA07	200mm	RFAB	H	PA07	300mm	
Qual details are p	rovided in the	Qual Data Sec	ction.				
Reason for Chan	ige:						
Continuity of supp	oly						
Anticipated impa	act on Form,	Fit, Function	, Quality or Rel	iability (	positive	/ negative):	
None							
Changes to prod	uct identifica	ation resultir	ng from this PCI	N:			
Fab Site Inform	ation:						
Chip Site	-	Origin Code 0L)	Chip Site Co Code (21		Chip Site City		
DP1DM5 DM5 USA					Dallas		
RFAB RFB USA Richardson							
Sample product sl	hipping label (	100000000000	-				
INSTRUMENTS MADE IN: Malaysia 2DC: 2Q: MSL 2/260C/1 YEAF MSL 1/235C/UNLIM OPT: ITEM:	39		(31T)LOT: 3959 (4W) TKY(1T) 75 (P) (2P) REV: (V)	0) 0336 047MLA 52348351 0033317			
LBL: 5A (L)T	0:1750		(20L) <u>CSO: SHE</u> (21 (22L) ASO: MLA (23)	L) CCO:USA L) ACO:MYS			
Product Affected	1:						
					DA 00 44 4		
DAC5311IDCKR	DAC63	11IDCKT	DAC8311IDCK	R	DAC8411	IDCKR	
DAC5311IDCKR DAC5311IDCKT		11IDCKT 11IDCKR	DAC8311IDCK DAC8311IDCK		DAC8411		

### Qualification Report Approve Date 24-MARCH -2023

#### Qualification Results

### Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Name	Condition	Duration	Qual Device: DAC7311IDCKT	QBS Process Reference: <u>CD3232A1YFFR</u>	QBS Process Reference: <u>CD3232A1YFFR</u>	QBS Process Reference: INA231AIYFDR	QBS Process Reference: INA231BIYFDR	QBS Process Reference: <u>DRV401AIRGWR</u>
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	3/231/0	3/231/0	-	-	-
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	-	3/231/0	3/231/0	-	-	-
тс	A4	Temperature Cycle	-55C/125C	700 Cycles	-	3/231/0	3/231/0	-		-
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	3/231/0	3/231/0	1/77/0	2/154/0	-
HTOL	81	Life Test	140C	480 Hours	-	1/77/0	2/154/0	-	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	1/77/0	2/154/0	2/154/0
ELFR	<b>B</b> 2	Early Life Failure Rate	125C	48 Hours	-	1/1000/0	2/2000/0	1/1000/0	2/2000/0	
ESD	E2	ESD CDM	-	250 Volts	1/3/0	-	-	1/3/0	2/6/0	2/6/0
ESD	E2	ESD HBM	-	1000 Volts	1/3/0	3/9/0	3/9/0	1/3/0	2/6/0	2/6/0
LU	E4	Latch-Up	Per JESD78	-	1/3/0	3/9/0	3/9/0	1/6/0	2/12/0	2/6/0 <sup>2,3</sup>
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	1/30/0	1/30/0	2/60/0	1/30/0
FTY	E6	Final Test Yield	-	-	1/Pass	-	-	-	-	-

QBS: Qual By Similarity

Qual Device DAC7311IDCKT is qualified at MSL1 260C

Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

### Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

Waiver from CF
Passes room and hot.
Passes room and hot.

For questions regarding this notice, e-mails can be sent to the contact shown below or your local Field Sales Representative.

Location	E-Mail
WW Change Management Team	PCN ww admin team@list.ti.com

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